

GTT2623

P-CHANNEL ENHANCEMENT MODE POWER MOSFET

BV _{DSS}	-30V
RDS(ON)	170mΩ
I _D	-2.0A

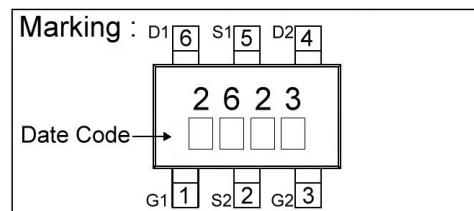
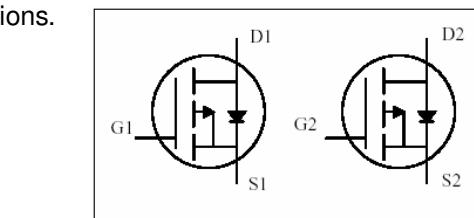
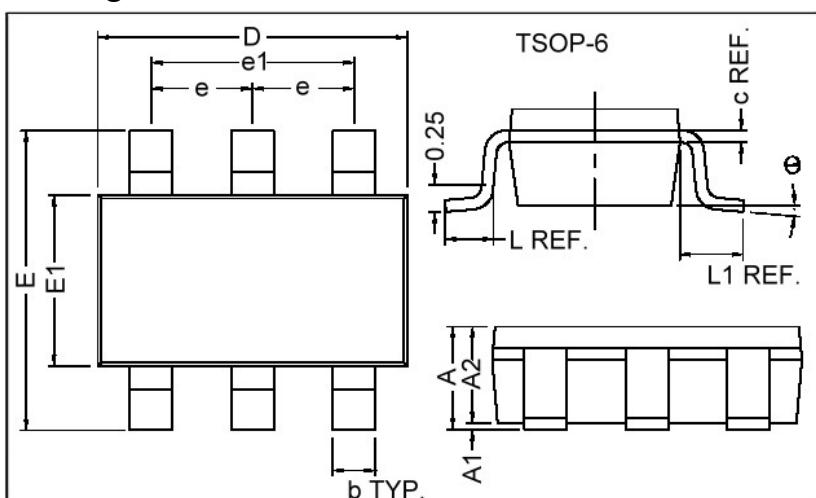
Description

The GTT2623 utilized advanced processing techniques to achieve the lowest possible on-resistance, extremely efficient and cost-effectiveness device.

The GTT2623 is universally used for all commercial-industrial applications.

Features

- *Low Gate Charge
- *Low On-resistance

Package Dimensions

REF.	Millimeter		REF.	Millimeter	
	Min.	Max.		Min.	Max.
A	1.10	MAX.	L	0.45	REF.
A1	0	0.10	L1	0.60	REF.
A2	0.70	1.00	θ	0°	10°
c	0.12	REF.	b	0.30	0.50
D	2.70	3.10	e	0.95	REF.
E	2.60	3.00	e1	1.90	REF.
E1	1.40	1.80			

Absolute Maximum Ratings

Parameter	Symbol	Ratings	Unit
Drain-Source Voltage	V _{DS}	-30	V
Gate-Source Voltage	V _{GS}	±20	V
Continuous Drain Current ³	I _D @TA=25°C	-2	A
Continuous Drain Current ³	I _D @TA=70°C	-1.6	A
Pulsed Drain Current ¹	I _{DM}	-20	A
Total Power Dissipation	P _D @TA=25°C	1.2	W
Linear Derating Factor		0.01	W/°C
Operating Junction and Storage Temperature Range	T _j , T _{stg}	-55 ~ +150	°C

Thermal Data

Parameter	Symbol	Value	Unit
Thermal Resistance Junction-ambient ³ Max.	R _{thj-a}	110	°C/W

Electrical Characteristics ($T_j = 25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
Drain-Source Breakdown Voltage	BV_{DSS}	-30	-	-	V	$\text{V}_{\text{GS}}=0, \text{I}_D=-250\mu\text{A}$
Breakdown Voltage Temperature Coefficient	$\Delta \text{BV}_{\text{DSS}} / \Delta T_j$	-	-0.02	-	V/ $^\circ\text{C}$	Reference to 25°C , $\text{I}_D=-1\text{mA}$
Gate Threshold Voltage	$\text{V}_{\text{GS}(\text{th})}$	-1.0	-	-3.0	V	$\text{V}_{\text{DS}}=\text{V}_{\text{GS}}, \text{I}_D=-250\mu\text{A}$
Forward Transconductance	g_{fs}	-	2	-	S	$\text{V}_{\text{DS}}=-5\text{V}, \text{I}_D=-2.0\text{A}$
Gate-Source Leakage Current	I_{GSS}	-	-	± 100	nA	$\text{V}_{\text{GS}}= \pm 20\text{V}$
Drain-Source Leakage Current($T_j=25^\circ\text{C}$)	I_{DSS}	-	-	-1	uA	$\text{V}_{\text{DS}}=-30\text{V}, \text{V}_{\text{GS}}=0$
Drain-Source Leakage Current($T_j=70^\circ\text{C}$)		-	-	-25	uA	$\text{V}_{\text{DS}}=-24\text{V}, \text{V}_{\text{GS}}=0$
Static Drain-Source On-Resistance ²	$\text{R}_{\text{DS}(\text{ON})}$	-	-	170	m Ω	$\text{V}_{\text{GS}}=-10\text{V}, \text{I}_D=-2.0\text{A}$
		-	-	280		$\text{V}_{\text{GS}}=-4.5\text{V}, \text{I}_D=-1.6\text{A}$
Total Gate Charge ²	Q_g	-	2.8	4.5	nC	$\text{I}_D=-2.0\text{A}$ $\text{V}_{\text{DS}}=-24\text{V}$ $\text{V}_{\text{GS}}=-4.5\text{V}$
Gate-Source Charge	Q_{gs}	-	0.5	-		
Gate-Drain ("Miller") Change	Q_{gd}	-	1.4	-		
Turn-on Delay Time ²	$\text{T}_{\text{d}(\text{on})}$	-	5	-	ns	$\text{V}_{\text{DS}}=-15\text{V}$ $\text{I}_D=-1.0\text{A}$ $\text{V}_{\text{GS}}=-10\text{V}$ $\text{R}_G=3.3\Omega$ $\text{R}_D=15\Omega$
Rise Time	T_r	-	6	-		
Turn-off Delay Time	$\text{T}_{\text{d}(\text{off})}$	-	15	-		
Fall Time	T_f	-	3	-		
Input Capacitance	C_{iss}	-	150	240	pF	$\text{V}_{\text{GS}}=0\text{V}$ $\text{V}_{\text{DS}}=-25\text{V}$ $f=1.0\text{MHz}$
Output Capacitance	C_{oss}	-	42	-		
Reverse Transfer Capacitance	C_{rss}	-	32	-		

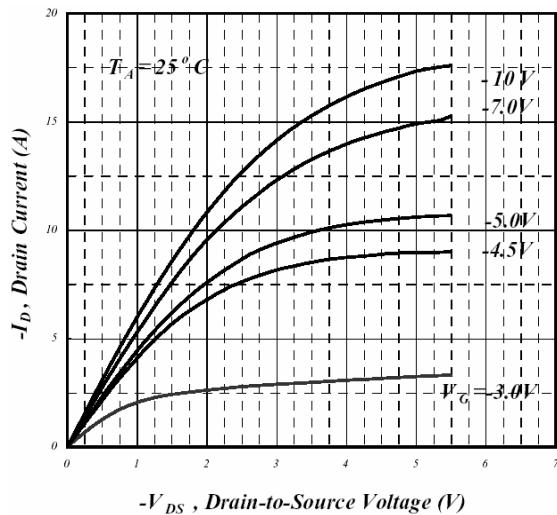
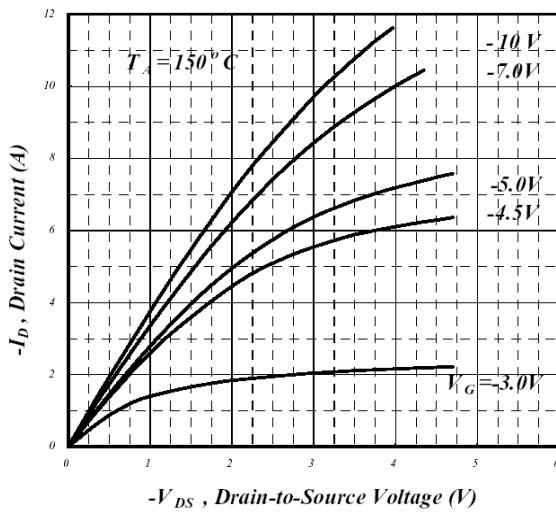
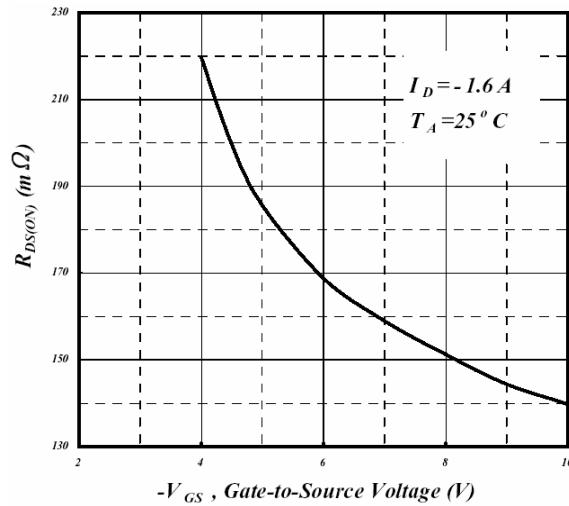
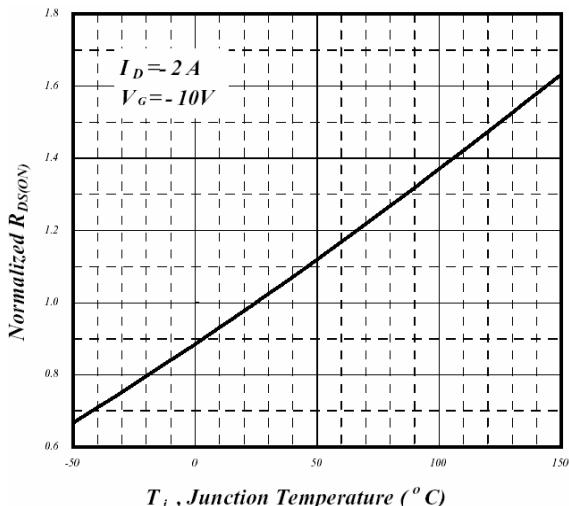
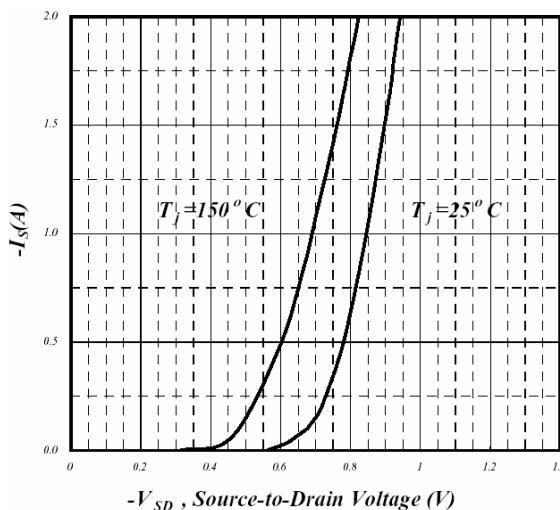
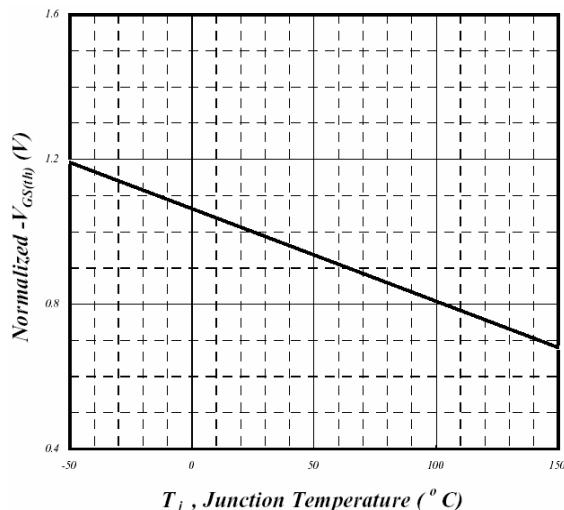
Source-Drain Diode

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
Forward On Voltage ²	V_{SD}	-	-	-1.2	V	$\text{I}_S=-1.0\text{A}, \text{V}_{\text{GS}}=0\text{V}$
Reverse Recovery Time ²	T_{rr}	-	20	-	ns	$\text{I}_S=-2.0\text{A}, \text{V}_{\text{GS}}=0\text{V}$
Reverse Recovery Charge	Q_{rr}	-	13	-	nC	$d\text{I}/dt=100\text{A}/\mu\text{s}$

Notes: 1. Pulse width limited by Max. junction temperature.

2. Pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$.

3. Surface mounted on 1 in² copper pad of FR4 board, $t \leq 5\text{sec}$; $180^\circ\text{C}/\text{W}$ when mounted on Min. copper pad.

Characteristics Curve**Fig 1. Typical Output Characteristics****Fig 2. Typical Output Characteristics****Fig 3. On-Resistance v.s. Gate Voltage****Fig 4. Normalized On-Resistance v.s. Junction Temperature****Fig 5. Forward Characteristics of Reverse Diode****Fig 6. Gate Threshold Voltage v.s. Junction Temperature**

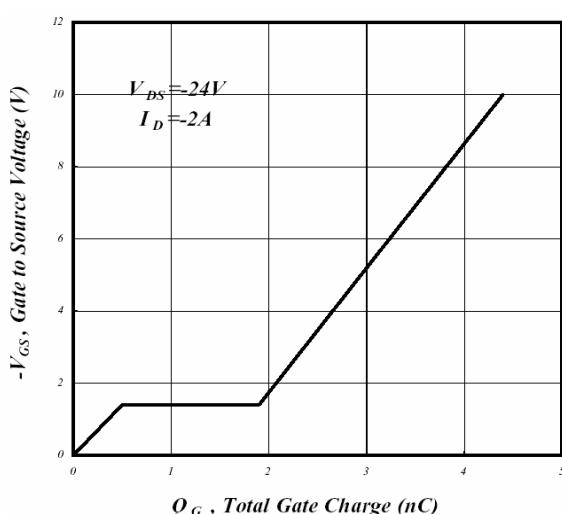


Fig 7. Gate Charge Characteristics

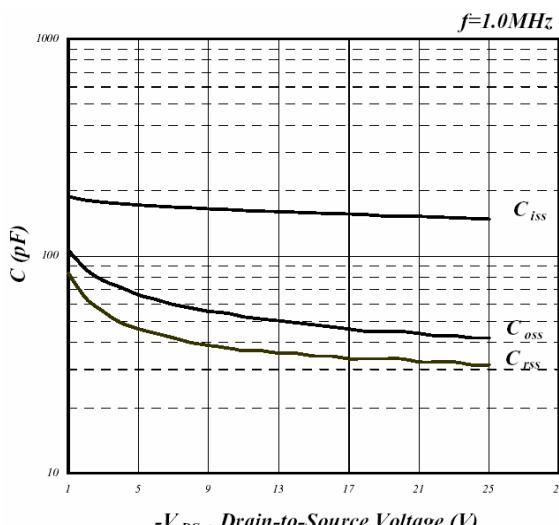


Fig 8. Typical Capacitance Characteristics

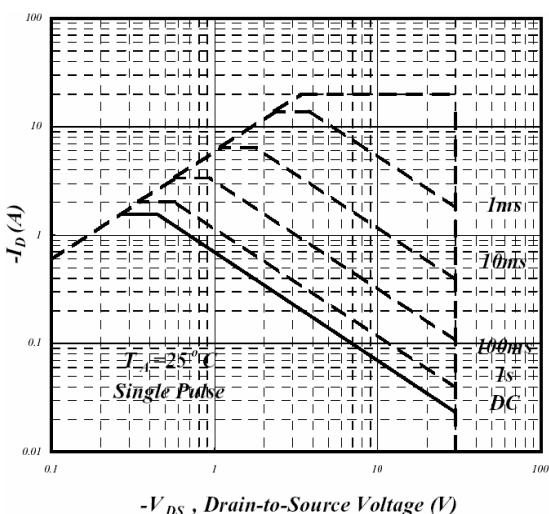


Fig 9. Maximum Safe Operating Area

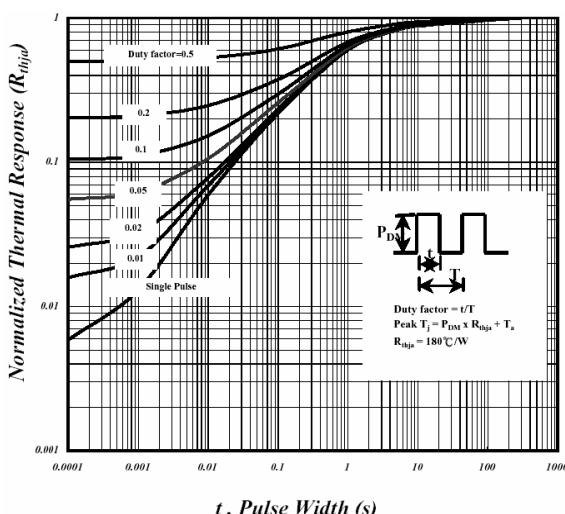


Fig 10. Effective Transient Thermal Impedance

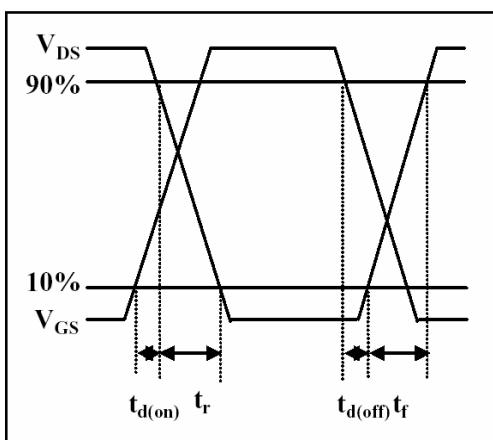


Fig 11. Switching Time Waveform

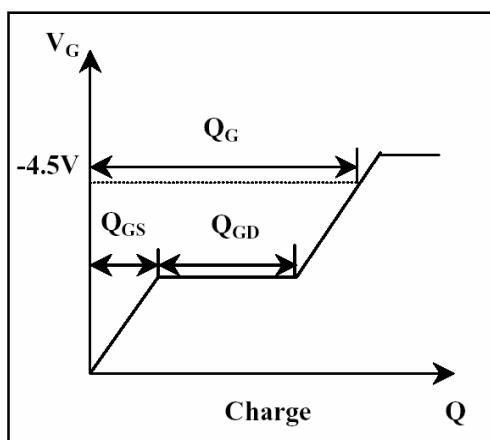


Fig 12. Gate Charge Waveform

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